

Abstract of the Disclosure:

Defective pixels of an image sensor are corrected by the device having an interpolator, a defect column memory, and a switch that changing the output signal under the control of the defect column memory. Depending on a defect signal from the defect column memory, input pixel data are output as output pixel data in a defect-free case and pixel data interpolated from adjacent pixel data are output as output pixel data in a defect case. The defect signal is generated from an image line address and an image column address such that a pointer memory is addressed by the image line address, wherein the pointer memory contains a pointer for each of at least some of the image lines, the pointer addressing a defect column memory with column numbers stored therein of defective image columns. The column number is read from the defect column memory, the column number is compared with the column address, and the defect signal is formed from the comparison.

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